

## STGWT20HP65FB

## Trench gate field-stop IGBT, HB series 650 V, 20 A high speed

Datasheet - production data

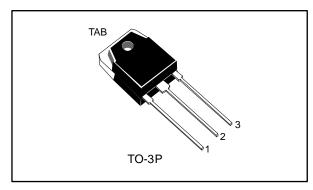
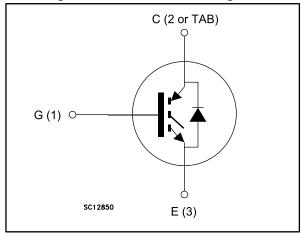


Figure 1: Internal schematic diagram



#### **Features**

- Maximum junction temperature: T<sub>J</sub> = 175 °C
- Minimized tail current
- $V_{CE(sat)} = 1.55 \text{ V (typ.)} @ I_C = 20 \text{ A}$
- Tight parameter distribution
- Co-packed diode for protection
- Safe paralleling
- Low thermal resistance

#### **Applications**

Power factor corrector (PFC)

### **Description**

This device is an IGBT developed using an advanced proprietary trench gate field-stop structure. The device is part of the new HB series of IGBTs, which represents an optimum compromise between conduction and switching loss to maximize the efficiency of any frequency converter. Furthermore, the slightly positive VCE(sat) temperature coefficient and very tight parameter distribution result in safer paralleling operation.

**Table 1: Device summary** 

Order code	Marking	Package	Packing	
STGWT20HP65FB	GWT20HP65FB	TO-3P	Tube	

Contents STGWT20HP65FB

## **Contents**

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STGWT20HP65FB Electrical ratings

# 1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
Vces	Collector-emitter voltage (V <sub>GE</sub> = 0 V)	650	V
1-	Continuous collector current at T <sub>C</sub> = 25 °C	40	Α
lc	Continuous collector current at T <sub>C</sub> = 100 °C	20	А
ICP <sup>(1)</sup>	Pulsed collector current	80	Α
$V_{GE}$	Gate-emitter voltage	±20	V
	Continuous forward current at T <sub>C</sub> = 25 °C <sup>(2)</sup>	5	Α
I <sub>F</sub>	Continuous forward current at T <sub>C</sub> = 100 °C	5	А
I <sub>FP</sub> <sup>(3)</sup>	Pulsed forward current	10	Α
Ртот	Total dissipation at T <sub>C</sub> = 25 °C	168	W
Tstg	Storage temperature range		°C
TJ	Operating junction temperature range	-55 to 175	

#### **Notes**

Table 3: Thermal data

Symbol	Parameter	Value	Unit
RthJC	Thermal resistance junction-case IGBT	0.9	
R <sub>thJC</sub>	Thermal resistance junction-case diode	5	°C/W
RthJA	Thermal resistance junction-ambient	50	

 $<sup>^{(1)}</sup>$ Pulse width limited by maximum junction temperature

<sup>&</sup>lt;sup>(2)</sup>Limited by wires

<sup>(3)</sup>Pulsed forward current

### 2 Electrical characteristics

 $T_J = 25$  °C unless otherwise specified

**Table 4: Static characteristics** 

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)CES</sub>	Collector-emitter breakdown voltage	$V_{GE} = 0 \text{ V}, I_C = 2 \text{ mA}$	650			V
		$V_{GE} = 15 \text{ V}, I_{C} = 20 \text{ A}$		1.55	2.0	
V <sub>CE(sat)</sub>	Collector-emitter saturation voltage	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 20 A, T <sub>J</sub> = 125 °C		1.65		V
	voltage	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 20 A, T <sub>J</sub> = 175 °C		1.75		
		I <sub>F</sub> = 5 A		2		
$V_{F}$	Forward on-voltage	I <sub>F</sub> = 5 A, T <sub>J</sub> = 125 °C		1.85		V
		I <sub>F</sub> = 5 A, T <sub>J</sub> = 175 °C		1.75		
$V_{\text{GE(th)}}$	Gate threshold voltage	$V_{CE} = V_{GE}$ , $I_C = 1 \text{ mA}$	5	6	7	V
I <sub>CES</sub>	Collector cut-off current	$V_{GE} = 0 \text{ V}, V_{CE} = 650 \text{ V}$			25	μA
I <sub>GES</sub>	Gate-emitter leakage current	$V_{CE} = 0 \text{ V}, V_{GE} = \pm 20 \text{ V}$			±250	nA

**Table 5: Dynamic characteristics** 

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Cies	Input capacitance		ı	2764	ı	
Coes	Output capacitance	$V_{CE} = 25 \text{ V, f} = 1 \text{ MHz,}$ $V_{GE} = 0 \text{ V}$	ı	80	ı	pF
Cres	Reverse transfer capacitance	VGL — V	-	60	-	
Qg	Total gate charge	Vcc = 520 V, Ic = 20 A,	ı	120	ı	
$Q_{ge}$	Gate-emitter charge	V <sub>GE</sub> = 15 V (see <i>Figure 27: "Gate</i>	-	20	-	nC
Qgc	Gate-collector charge	charge test circuit")	-	50	-	

Table 6: IGBT switching characteristics (inductive load)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(off)</sub>	Turn-off delay time	V <sub>CE</sub> = 400 V, I <sub>C</sub> = 20 A,	ı	139	ı	ns
$t_f$	Current fall time	$V_{GE} = 15 \text{ V}, R_G = 10 \Omega$ (see Figure 26: "Test circuit	ı	20	ı	ns
E <sub>off</sub> <sup>(1)</sup>	Turn-off switching energy	for inductive load switching")	ı	170	ı	μJ
t <sub>d(off)</sub>	Turn-off-delay time	V <sub>CE</sub> = 400 V, I <sub>C</sub> = 20 A,	-	147	-	ns
t <sub>f</sub>	Current fall time	$V_{GE} = 15 \text{ V}, R_G = 10 \Omega,$ $T_J = 175 \text{ °C}$ (see Figure 26: "Test circuit for inductive load switching")	ı	38	1	ns
E <sub>off</sub> <sup>(1)</sup>	Turn-off switching energy		-	353	-	μJ

#### Notes:

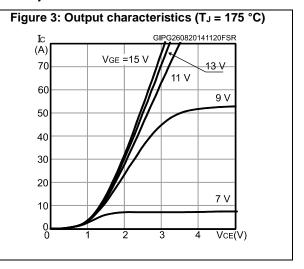


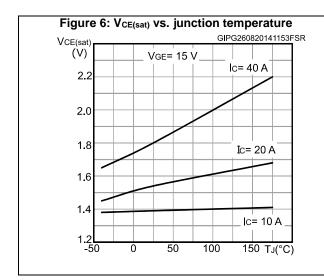
<sup>&</sup>lt;sup>(1)</sup>Including the tail of the collector current

Table 7: Diode switching characteristics (inductive load)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>rr</sub>	Reverse recovery time		-	140	-	ns
Qrr	Reverse recovery charge	$I_F = 5 \text{ A}, V_R = 400 \text{ V},$	ı	21	1	nC
Irrm	Reverse recovery current	V <sub>GE</sub> = 15 V, di/dt = 1000 A/µs	-	6.6	-	Α
dl <sub>rr</sub> /dt	Peak rate of fall of reverse recovery current during t <sub>b</sub>	(see Figure 26: "Test circuit for inductive load switching")	-	430	-	A/µs
Err	Reverse recovery energy		-	1.6	-	μJ
t <sub>rr</sub>	Reverse recovery time		-	200	-	ns
Qrr	Reverse recovery charge	$I_F = 5 A$ , $V_R = 400 V$ ,	-	47.3	-	nC
I <sub>rrm</sub>	Reverse recovery current	V <sub>GE</sub> = 15 V, T <sub>J</sub> = 175 °C, di/dt = 1000 A/µs (see Figure 26: "Test circuit for inductive load switching")	-	9.6	-	Α
dl <sub>rr</sub> /dt	Peak rate of fall of reverse recovery current during t <sub>b</sub>		-	428	-	A/µs
Err	Reverse recovery energy		-	3.2	-	μJ

## 2.1 Electrical characteristics (curves)





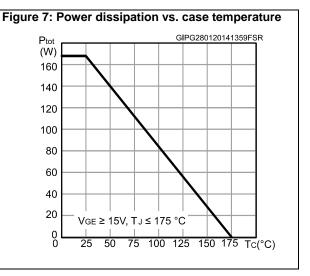
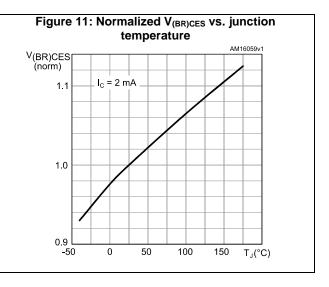
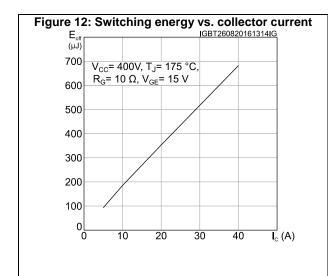


Figure 9: Collector current vs. switching frequency GIPG260820141342FSR Ic [A] 60 Tc=80 °C 50 40 Tc=100 °C 30 20 rectangular current shape, (duty cycle=0.5,  $V_{CC}$  = 400V,  $R_{G}$ =4.7 $\Omega_{r}$ 10  $V_{GE} = 0/15 \text{ V}, \text{ T}_{J} = 175 ^{\circ}\text{C})$ f [kH z] 10

Figure 10: Normalized V<sub>GE(th)</sub> vs. junction temperature AM16060v1 V<sub>GE(th)</sub> (norm)  $V_{CE} = V_{GE}$ ,  $I_C = 1 \text{ mA}$ 1.0 0.9 8.0 0.7 0.6 50 -50 0 100 150  $T_J(^{\circ}C)$ 





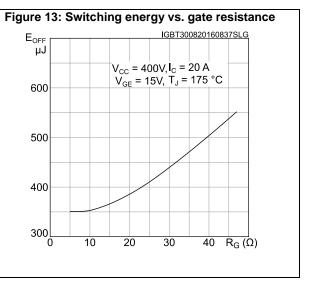


Figure 14: Switching energy vs. temperature

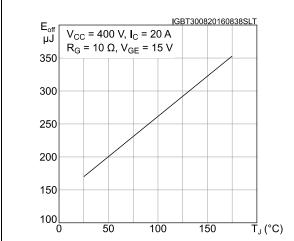


Figure 15: Switching energy vs. collector emitter voltage

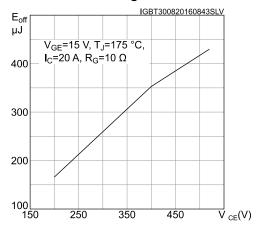


Figure 16: Switching times vs. collector current

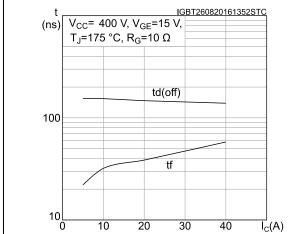


Figure 17: Switching time vs. gate resistance

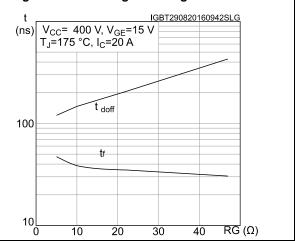


Figure 18: Capacitance variations

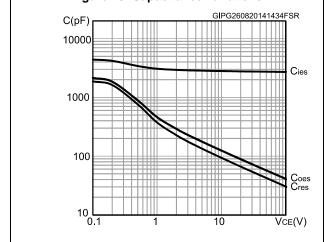


Figure 19: Gate charge vs. gate-emitter voltage

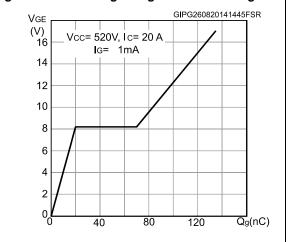


Figure 20: Diode V<sub>F</sub> vs. forward current

V<sub>F</sub>
(V)

2.6

T<sub>i</sub> = -40 °C

2.0

1.4

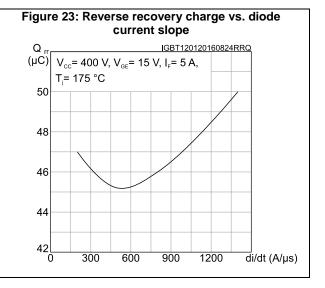
T<sub>i</sub> = 175 °C

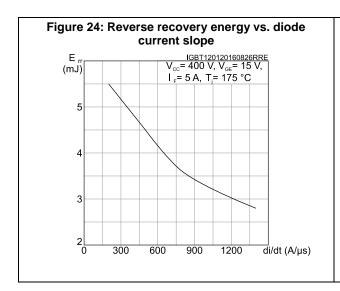
0.8

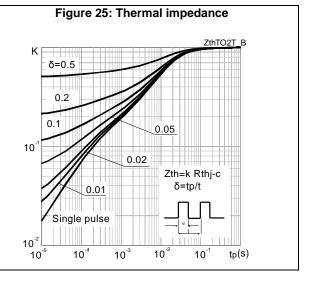
0.2

0 2 4 6 8 10 I<sub>F</sub> (A)

Figure 22: Reverse recovery time vs. diode current slope trr IGBT120120160820RRT  $V_{cc}$ = 400 V,  $V_{ge}$ = 15 V,  $I_{F}$ = 6 A, (ns) T<sub>i</sub>= 175 °C 350 300 250 200 150 100 0 300 600 900 1200 di/dt (A/µs)

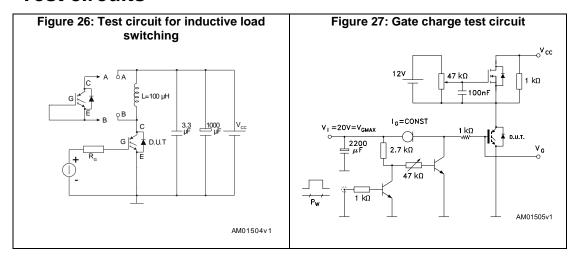


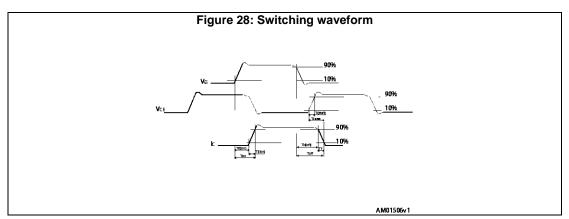




Test circuits STGWT20HP65FB

## 3 Test circuits





# 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.



# 4.1 TO-3P package information

Figure 29: TO-3P package outline

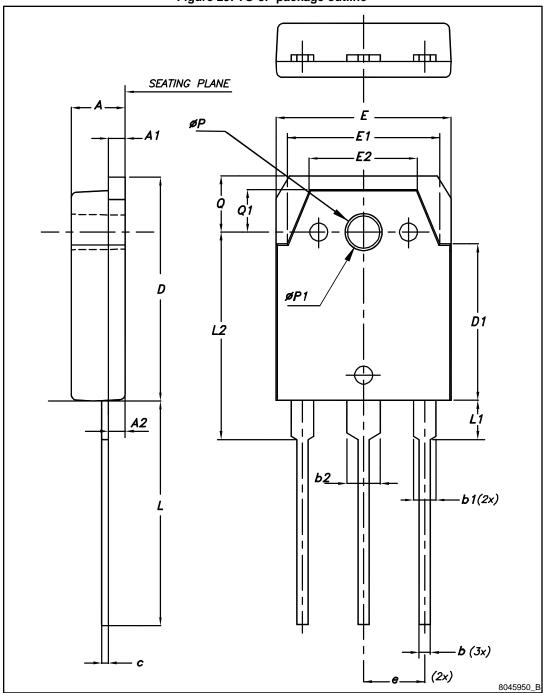


Table 8: TO-3P package mechanical data

Table 6. 10-3F package mechanical data					
Dim.		mm			
	Min.	Тур.	Max.		
А	4.60	4.80	5.00		
A1	1.45	1.50	1.65		
A2	1.20	1.40	1.60		
b	0.80	1.00	1.20		
b1	1.80	2.00	2.20		
b2	2.80	3.00	3.20		
С	0.55	0.60	0.75		
D	19.70	19.90	20.10		
D1	13.70	13.90	14.10		
Е	15.40	15.60	15.80		
E1	13.40	13.60	13.80		
E2	9.40	9.60	9.90		
е	5.15	5.45	5.75		
L	19.80	20.00	20.20		
L1	3.30	3.50	3.70		
L2	18.20	18.40	18.60		
ØP	3.30	3.40	3.50		
ØP1	3.10	3.20	3.30		
Q	4.80	5.00	5.20		
Q1	3.60	3.80	4		

Revision history STGWT20HP65FB

# 5 Revision history

**Table 9: Document revision history** 

Date	Revision	Changes
31-Aug-2016	1	First release.
28-Sep-2016	2	Datasheet promoted from preliminary to production data.
13-Dec-2016	3	Updated Figure 1: "Internal schematic diagram".  Updated Table 4: "Static characteristics" and Table 7: "Diode switching characteristics (inductive load)".  Added Figure 20: "Diode VF vs. forward current", Figure 21: "Reverse recovery current vs. diode current slope", Figure 22: "Reverse recovery time vs. diode current slope", Figure 23: "Reverse recovery charge vs. diode current slope" and Figure 24: "Reverse recovery energy vs. diode current slope".  Updated Figure 2: "Output characteristics (TJ = 25 °C)", Figure 12: "Switching energy vs. collector current" and Figure 17: "Switching time vs. gate resistance".  Minor text changes

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